

**Search Notes**

Application/Control No.

10/780,774

Examiner

Tu M. Nguyen

Applicant(s)/Patent under  
Reexamination

SHIRAKAWA ET AL.

Art Unit

3748

**SEARCHED**

Class	Subclass	Date	Examiner
60	274	6/2006	TMN
	276		
	277		
	285		
	301		
701	103		
	109		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search	6/2006	TMN